## Search Notes



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Examiner

Johnson, Ryan J

Applicant(s)/Patent Under Reexamination

YOSHIKAWA ET AL.

Art Unit

2817

## **SEARCHED**

| Class | Subclass            | Date      | Examiner     |  |  |
|-------|---------------------|-----------|--------------|--|--|
| 331   | 16,17,23            | 1/15/2008 | Ryan Johnson |  |  |
| 332   | 144,145,103,127,128 | 1/15/2008 | Ryan Johnson |  |  |
| 375   | 302,308,373,374,376 | 1/15/2008 | Ryan Johnson |  |  |
| 327   | 156,157             | 1/15/2008 | Ryan Johnson |  |  |
| 455   | 102,110             | 1/15/2008 | Ryan Johnson |  |  |

## **SEARCH NOTES**

| Search Notes         | Date      | Examiner     |  |  |
|----------------------|-----------|--------------|--|--|
| See EAST history     | 1/15/2008 | Ryan Johnson |  |  |
| IEEE search          | 1/15/2008 | Ryan Johnson |  |  |
| Google search        | 1/15/2008 | Ryan Johnson |  |  |
| Emailed Joseph Chang | 1/15/2008 | Ryan Johnson |  |  |

## **INTERFERENCE SEARCH**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |

Part of Paper No.: 20080115